

<b>Notice of References Cited</b>	Application/Control No. 10/530,515	Applicant(s)/Patent Under Reexamination SUNAGAWA ET AL.	
	Examiner Michael Bernshteyn	Art Unit 1713	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,447,913	09-2002	Watanabe et al.	428/413
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	CN 1123302 A	05-1996	China	DING et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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